IXYS

Preliminary Technical Information

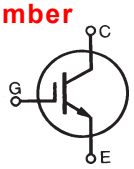
GenX3™ 600V IGBT

IXGH64N60A3
IXGT64N60A3*

*Obsolete Part Number

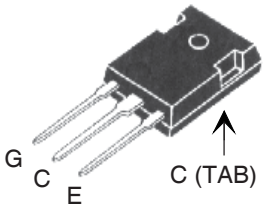
V_{CES} = 600V
I_{C110} = 64A
$V_{CE(sat)} \leq$ 1.35V

Ultra-lowVsat PT IGBTs for up to 5 kHz switching

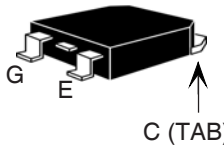


Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_C = 25°C to 150°C	600	V
V_{CGR}	T_J = 25°C to 150°C, R_{GE} = 1MΩ	600	V
V_{GES}	Continuous	± 20	V
V_{GEM}	Transient	± 30	V
I_{C110}	T_C = 110°C	64	A
I_{CM}	T_C = 25°C, 1ms	400	A
SSOA (RBSOA)	V_{GE} = 15V, T_{VJ} = 125°C, R_G = 3Ω Clamped inductive load @ ≤ 600V	I_{CM} = 100	A
P_C	T_C = 25°C	460	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6mm (0.062 in.) from case for 10s	300	°C
T_{SOLD}	Plastic body for 10 seconds	260	°C
M_d	Mounting torque (TO-247)	1.13/10	Nm/lb.in.
Weight	TO-247	6	g
	TO-268	5	g

TO-247 (IXGH)



TO-268 (IXGT)



G = Gate C = Collector
E = Emitter TAB = Collector

Symbol	Test Conditions (T_J = 25°C unless otherwise specified)	Characteristic Values Min.	Typ.	Max.	
BV_{CES}	I_C = 250μA, V_{GE} = 0V	600			V
$V_{GE(th)}$	I_C = 250μA, V_{CE} = V_{GE}	3.0		5.0	V
I_{CES}	V_{CE} = V_{CES}			50	μA
	V_{GE} = 0V, T_J = 125°C			500	μA
I_{GES}	V_{CE} = 0V, V_{GE} = ± 20V			±100	nA
$V_{CE(sat)}$	I_C = 50A, V_{GE} = 15V, Note 1		1.20	1.35	V

Features

- Optimized for low conduction losses
- Square RBSOA
- International standard packages

Advantages

- High power density
- Low gate drive requirement

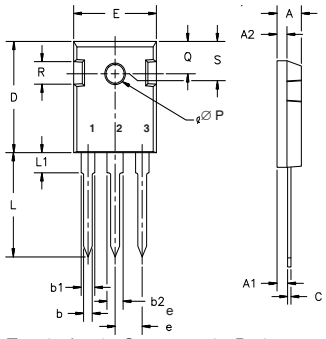
Applications

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts
- Inrush Current Protection Circuits

Symbol	Test Conditions (T_J = 25°C unless otherwise specified)	Characteristic Values Min.	Typ.	Max.	
g_{fs}	I_C = 50A, V_{CE} = 10V, Note 1	40	70		S
C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz		4850		pF
C_{oes}			270		pF
C_{res}			66		pF
Q_g	I_C = 50A, V_{GE} = 15V, V_{CE} = 0.5 • V_{CES}		167		nC
Q_{ge}			28		nC
Q_{gc}			60		nC
$t_{d(on)}$	**Inductive load, T_J = 25°C** I_C = 50A, V_{GE} = 15V V_{CE} = 480V, R_G = 3Ω		26		ns
t_{ri}			40		ns
E_{on}			1.42		mJ
$t_{d(off)}$			268		ns
t_{fi}			222		ns
E_{off}			3.28		mJ
$t_{d(on)}$	**Inductive load, T_J = 125°C** I_C = 50A, V_{GE} = 15V V_{CE} = 480V, R_G = 3Ω		25		ns
t_{ri}			40		ns
E_{on}			2.76		mJ
$t_{d(off)}$			415		ns
t_{fi}			362		ns
E_{off}			6.00		mJ
R_{thJC}				0.27	°C/W
R_{thCS}			0.25		°C/W

Note 1: Pulse test, t ≤ 300µs, duty cycle, d ≤ 2%.

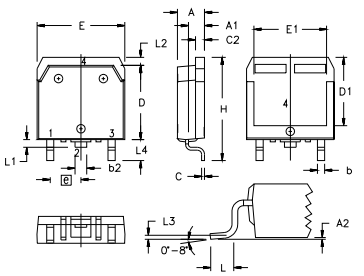
TO-247 (IXGH) Outline



Terminals: 1 - Gate 2 - Drain
3 - Source Tab - Drain

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.7	5.3	.185	.209
A_1	2.2	2.54	.087	.102
A_2	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b_1	1.65	2.13	.065	.084
b_2	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15 BSC		242 BSC	

TO-268 (IXGT) Outline



SYM	INCHES MIN	MAX	MILLIMETERS MIN	MAX
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215 BSC		5.45 BSC	
H	.736	.752	18.70	19.10
L	.094	.106	2.40	2.70
L1	.047	.055	1.20	1.40
L2	.039	.045	1.00	1.15
L3	.010 BSC		0.25 BSC	
L4	.150	.161	3.80	4.10

PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from data gathered during objective characterizations of preliminary engineering lots; but also may yet contain some information supplied during a pre-production design evaluation. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

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Fig. 1. Output Characteristics @ 25ºC

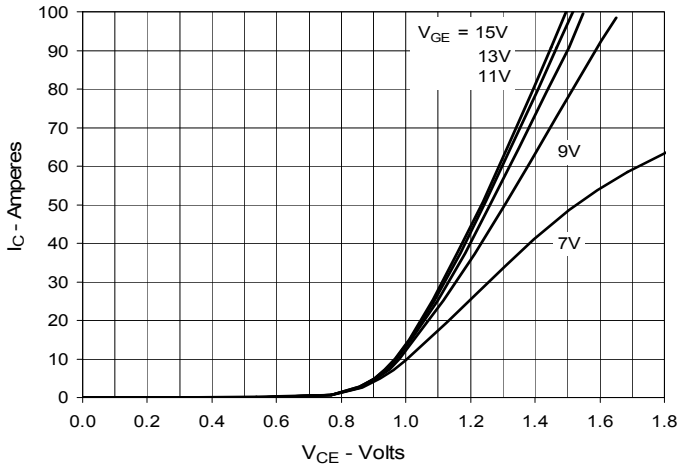

Fig. 2. Extended Output Characteristics @ 25ºC

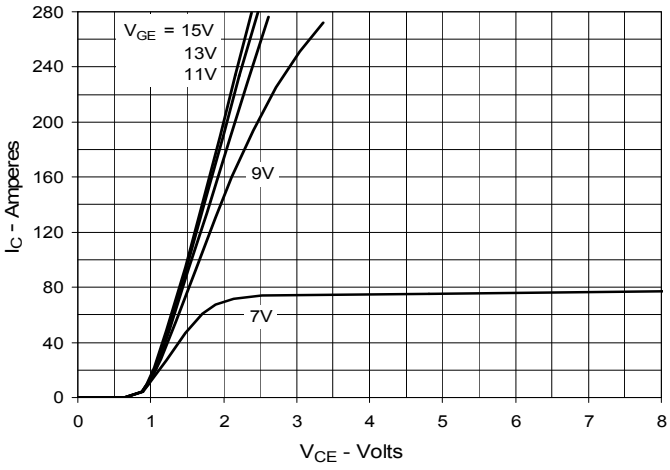

Fig. 3. Output Characteristics @ 125ºC

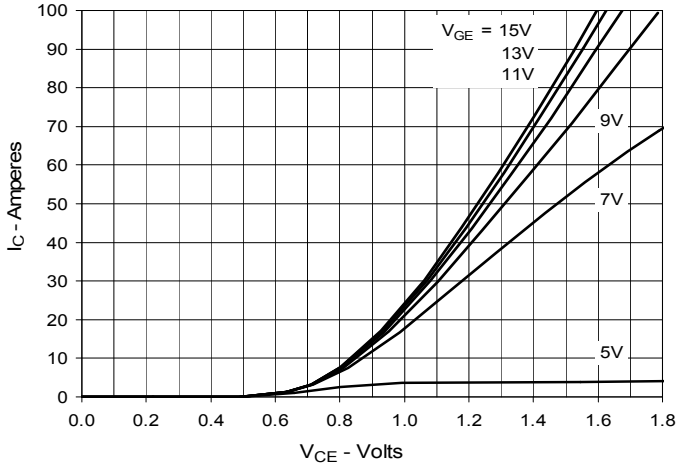

Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

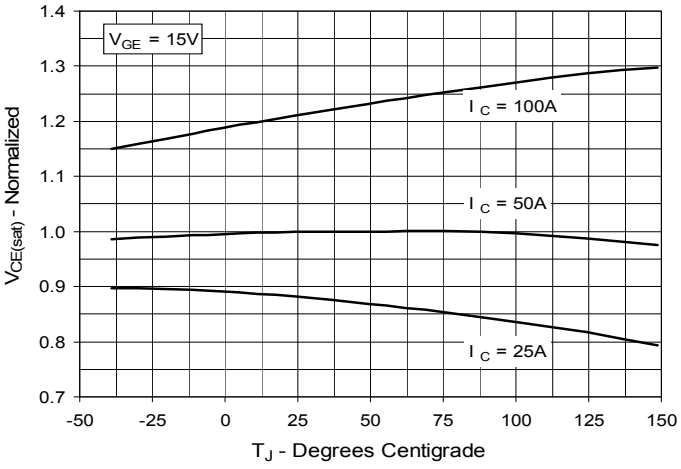

Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

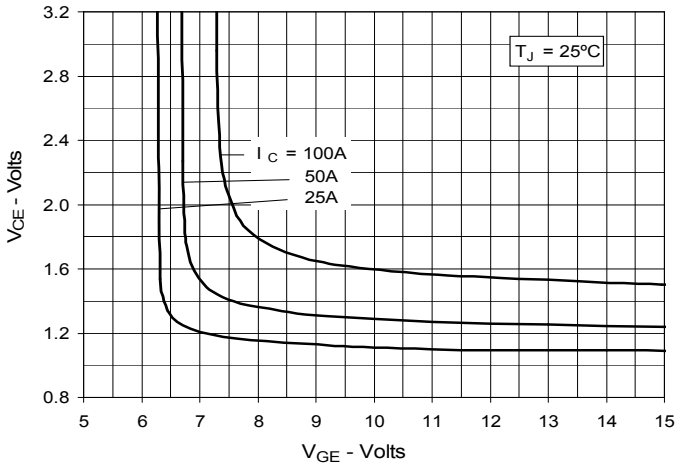

Fig. 6. Input Admittance

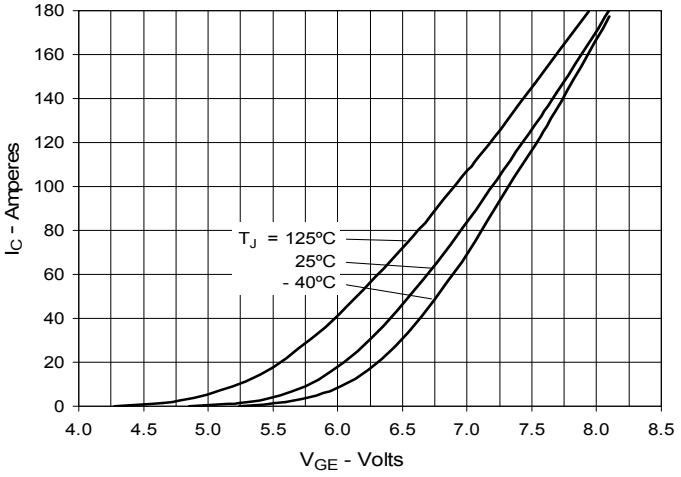

Fig. 7. Transconductance

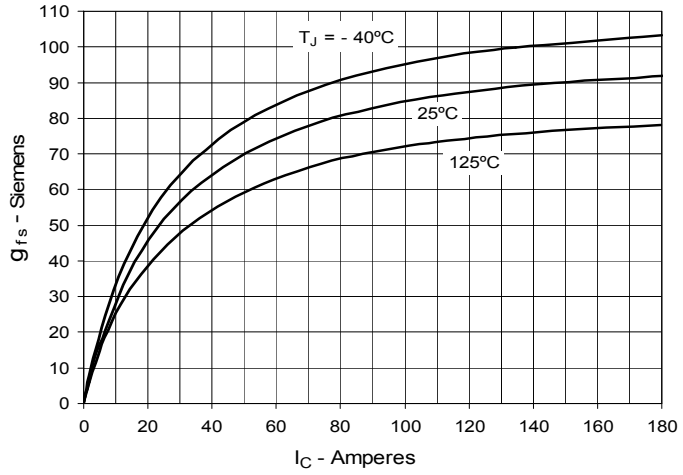

Fig. 8. Gate Charge

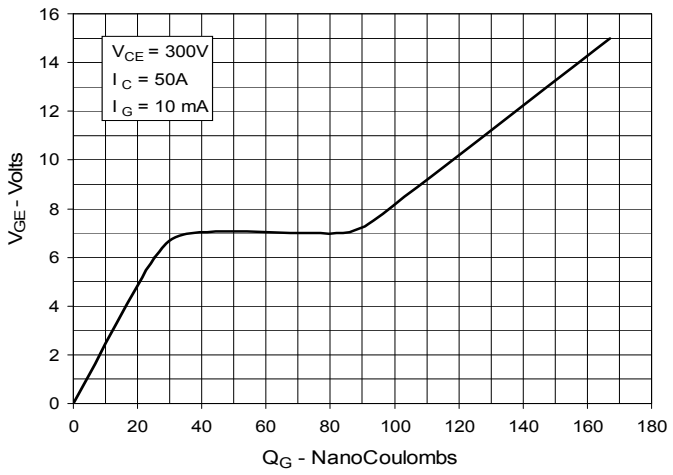

Fig. 9. Capacitance

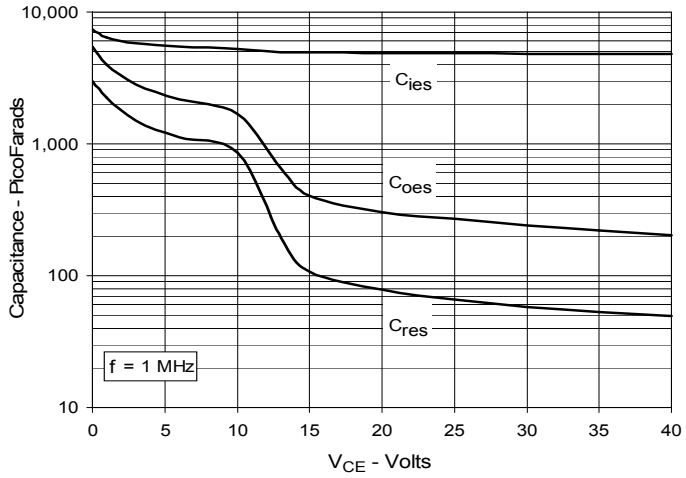

Fig. 10. Reverse-Bias Safe Operating Area

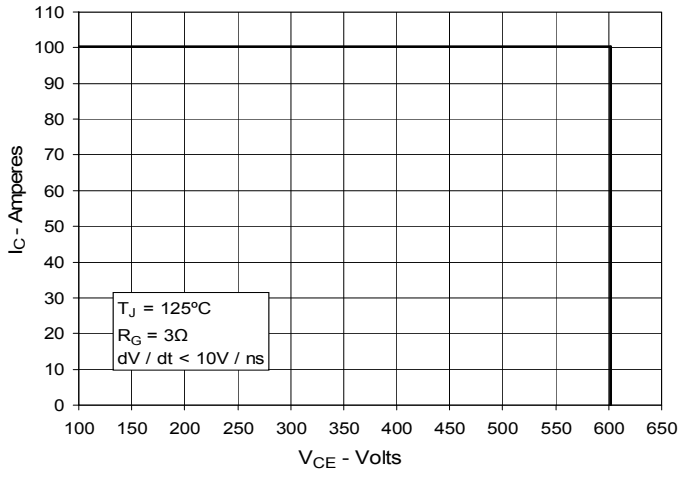

Fig. 11. Maximum Transient Thermal Impedance

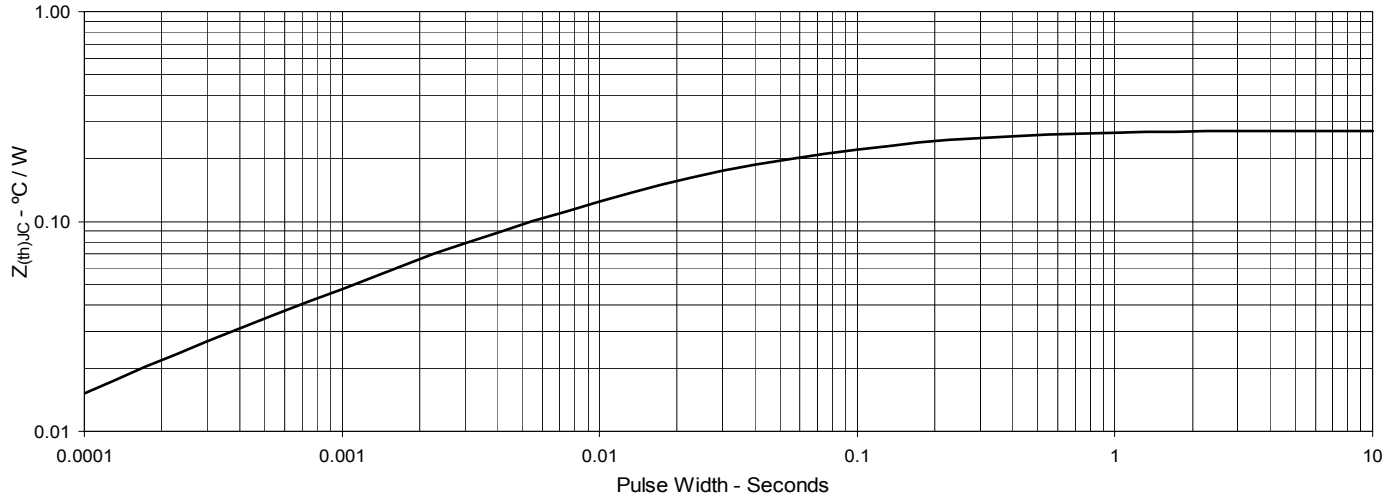

Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance

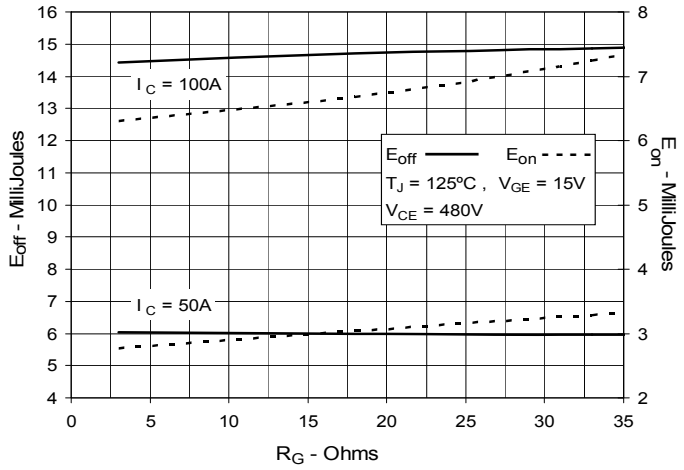

Fig. 13. Inductive Switching Energy Loss vs. Junction Temperature

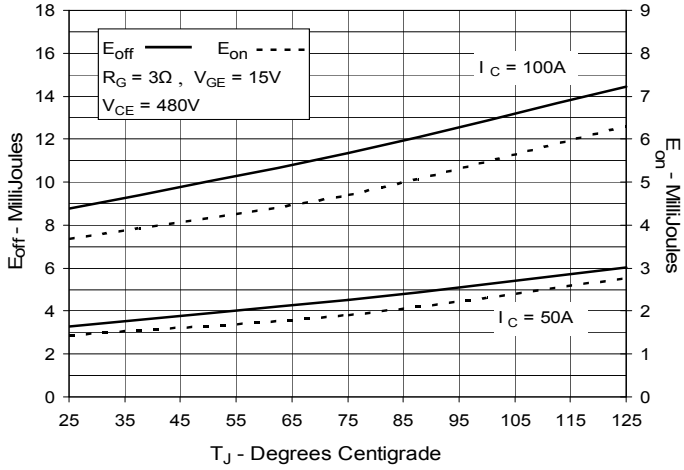

Fig. 14. Inductive Switching Energy Loss vs. Collector Current

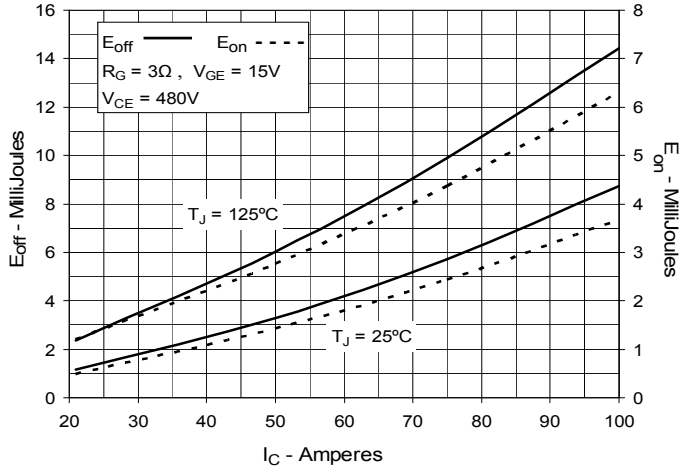

Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance

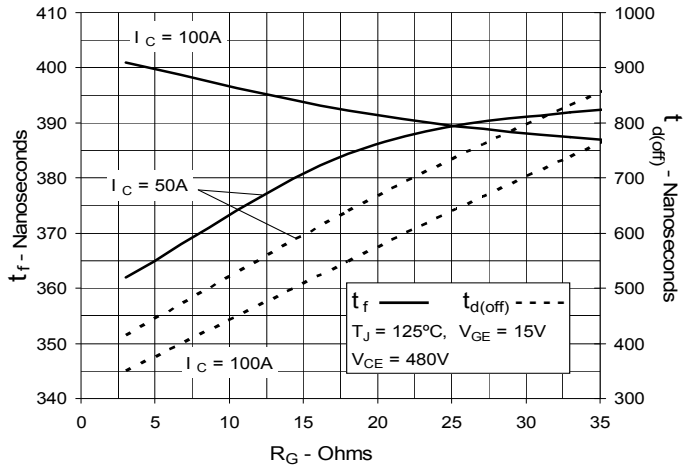

Fig. 16. Inductive Turn-off Switching Times vs. Collector Current

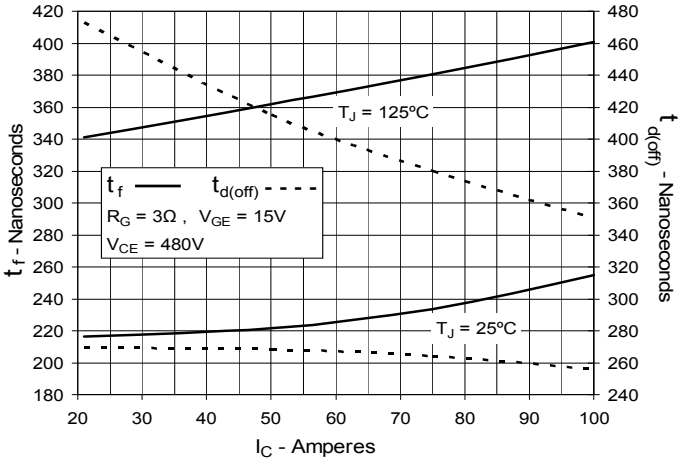

Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature

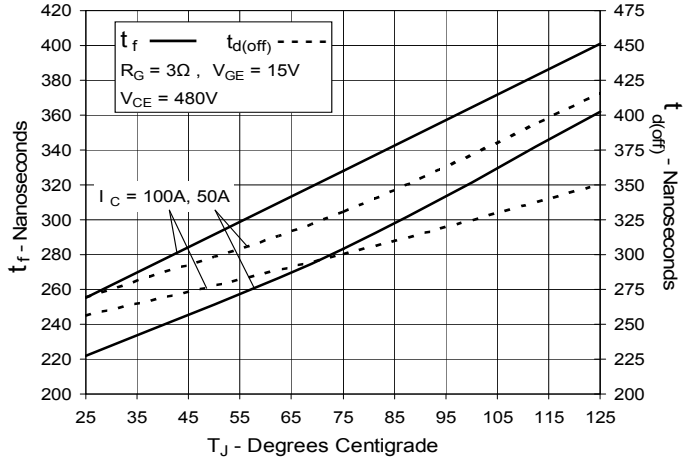

Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance

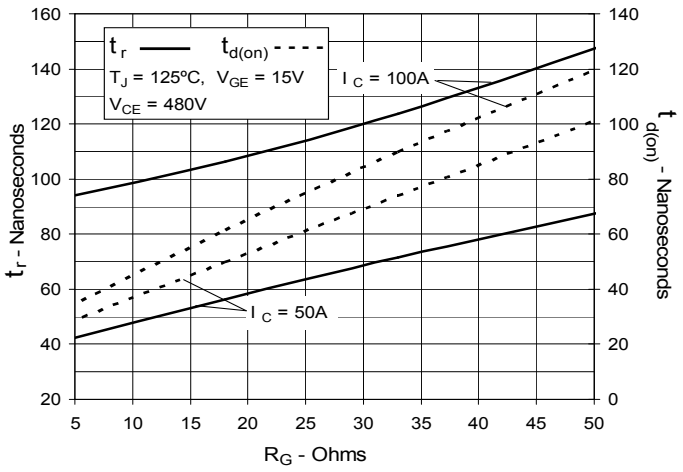

Fig. 19. Inductive Turn-on Switching Times vs. Junction Temperature

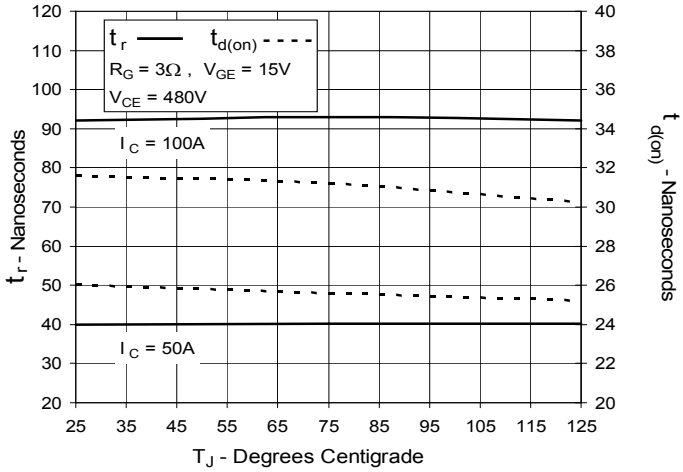

Fig. 20. Inductive Turn-on Switching Times vs. Collector Current